

C0603C682J3GECTU

Aliases (C0603C682J3GEC7867)

ESD SMD Comm COG, Ceramic, 6,800 pF, 5%, 25 VDC, COG, SMD, MLCC, Temperature Stable, Electro Static Discharge, Class I, 0603, 0.5 mm



General Information	
Series	ESD SMD Comm COG
Style	SMD Chip
Description	SMD, MLCC, Temperature Stable, Electro Static Discharge, Class I
Features	Temperature Stable, Low ESR, Class I
RoHS	Yes
Termination	Tin
Marking	No
AEC-Q200	No
Typical Component Weight	3.7 mg
Shelf Life	78 Weeks
MSL	1

0603
1.6mm +/-0.15mm
0.8mm +/-0.15mm
0.8mm +/-0.07mm
0.5mm MIN
0.35mm +/-0.15mm

Т	0.8mm +/-0.07mm	Voltage DC	25 VDC
S	0.5mm MIN	ESD Level per AEC-Q200	25,000 V ESD Level
В	0.35mm +/-0.15mm	Dielectric Withstanding Voltage	62.5 VDC
		Temperature Range	-55/+125°C
Packaging Specifications		Temp. Coefficient	COG
Packaging	T&R, 180mm, Paper Tape	Capacitance Change with 30 ppm/C, 1kHz 1.0Vrr	
Packaging Quantity	4000	Reference to +25°C and 0 VDC Applied (TCC)	,
		Dissipation Factor	0.1% 1 kHz 1.0\/rms

Specifications	
Capacitance	6,800 pF
Measurement Condition	1 kHz 1.0Vrms
Tolerance	5%
Voltage DC	25 VDC
ESD Level per AEC-Q200	25,000 V ESD Level
Dielectric Withstanding Voltage	62.5 VDC
Temperature Range	-55/+125°C
Temp. Coefficient	COG
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1kHz 1.0Vrms
Dissipation Factor	0.1% 1 kHz 1.0Vrms
Aging Rate	0% Loss/Decade Hour
Insulation Resistance	100 GOhms

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